

Search Notes

Application/Control No.

10/551,623

Examiner

Chuck Mah

Applicant(s)/Patent under
Reexamination

OSHIMA ET AL.

Art Unit

3677

SEARCHED

Class	Subclass	Date	Examiner
16	366 369 369		
	302		
	303 330		
379	433.12 433.13		
455	575.1, 575.4 575.3, 575.8 550.1, 50.3		
361	814, 680-683		
348	373, 794 333.06		
		1/4/09 cy	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR